

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination YOKOYAMA ET AL.	
		Examiner Sin J. Lee	Art Unit 1752	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0054287	03-2003	Yasunami et al.	430/270.1
*	B	US-2003/0039916	02-2003	Adegawa et al.	430/270.1
*	C	US-2001/0041769	11-2001	Iwasawa et al.	524/588
	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP1-197520	08-1989	Japan	Watabe et al.	N/A
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chemical Abstract 112:66778 (English abstract for JP 1-197520).
	V	JPO English abstract for JP 1-197520.
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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